TOSHIBA Power MOS FET Module Silicon N Channel MOS Type (Four L²-π-MOSV in One)

MP4411

High Power, High Speed Switching Applications
For Printer Head Pin Driver and Pulse Motor Driver
For Solenoid Driver

- 4-V gate drivability
- Small package by full molding (SIP 12 pin)
- High drain power dissipation (4-device operation)
 : PT = 28 W (Tc = 25°C)
- Low drain-source ON resistance: $RDS(ON) = 0.28 \Omega \text{ (typ.)}$
- High forward transfer admittance: $|Y_{fs}| = 3.5 \text{ S (typ.)}$
- Low leakage current: $I_{GSS} = \pm 10 \mu A \text{ (max) (V}_{GS} = \pm 16 \text{ V)}$

 $I_{DSS} = 100 \, \mu A \, (max) \, (V_{DS} = 100 \, V)$

• Enhancement-mode: $V_{th} = 0.8 \text{ to } 2.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA)}$

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	100	V
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	100	V
Gate-source voltage		V_{GSS}	±20	V
Drain current	DC	I _D	3	Α
	Pulse	I_{DP}	12	^
Drain power dissipation (1-device operation, Ta =	: 25°C)	P _D	2.2	W
Drain power dissipation	Ta = 25°C	-	4.4	14/
(4-device operation)	Tc = 25°C	P_{DT}	28	W
Single pulse avalanche e	nergy (Note 1)	E _{AS}	140	mJ
Avalanche current		I _{AR}	3	Α
Repetitive avalanche energy (Note 2)	1 device operation	E _{AR}	0.22	mJ
	4 devices operation	E _{ART}	0.44	IIIJ
Channel temperature	_	T _{ch}	150	°C
Storage temperature ran	ge	T _{stg}	-55 to 150	°C

Note 1: Condition for avalanche energy (single pulse) measurement

 $V_{DD} = 50 \text{ V}$, starting $T_{ch} = 25^{\circ}\text{C}$, L = 20 mH, $R_{G} = 25 \Omega$, $I_{AR} = 3 \text{ A}$

Note 2: Repetitive rating; pulse width limited by maximum channel temperature

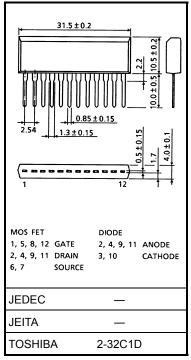
Note 3: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Please handle with caution.

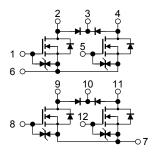
Industrial Applications

Unit: mm



Weight: 3.9 g (typ.)

Array Configuration



Thermal Characteristics

Characteristics	Symbol	Max	Unit	
Thermal resistance from channel to ambient	ΣR _{th (ch-a)}	28.4	°C/W	
(4-device operation, Ta = 25°C)				
Thermal resistance from channel to case	ΣR _{th (ch-c)}	4.46	°C/W	
(4-device operation, Tc = 25°C)	, ,			
Maximum lead temperature for soldering purposes	TL	260	°C	
(3.2 mm from case for t = 10 s)	_			

Electrical Characteristics (Ta = 25°C)

Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ
Drain cut-off curre	ent	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source brea	akdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	100	_	_	V
Gate threshold vo	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	8.0	_	2.0	V
Drain course ON	registance	Pro (ou)	V _{GS} = 4 V, I _D = 2 A	_	0.36	0.45	
Drain-source ON resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 2 A	_	0.28	0.35	Ω	
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 2 A	1.5	3.5	_	S
Input capacitance	•	C _{iss}		_	280	_	pF
Reverse transfer	capacitance	C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	50	_	pF
Output capacitan	ce	Coss		_	105	_	pF
Rise time Turn-on time Switching time Fall time Turn-off time	t _r	10 V I _D = 2 A V _{OUT}	_	20	_		
	Turn-on time	t _{on}	VGS Q Q Q Q Q Q Q Q Q Q Q Q Q Q Q Q Q Q Q	_	50	_	no
	t _f	C V _{DD} ≈ 50 V		40	_	ns	
	Turn-off time	t _{off}	V_{IN} : t_r , $t_f < 5$ ns, duty $\le 1\%$, $t_W = 10 \ \mu s$	I	170	_	
Total gate charge (gate-source plus gate-drain)		Qg	V _{DD} ≈ 80 V, V _{GS} = 10 V, I _D = 3 A		13.5		nC
Gate-source charge		Q _{gs}		_	8.5	_	nC
Gate-drain ("miller") charge		Q _{gd}		_	5	_	nC



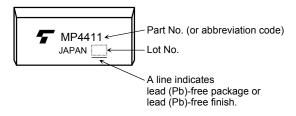
Source-Drain Diode Ratings and Characteristics (Ta = 25°C)

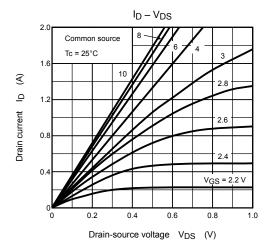
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current	I_{DR}	_	_	_	3	Α
Pulse drain reverse current	I _{DRP}	_	_	_	12	Α
Diode forward voltage	V_{DSF}	IDR = 3 A, VGS = 0 V	_	_	-1.5	V
Reverse recovery time	t _{rr}	IDR = 3 A, VGS = 0 V, dIDR/dt = 50 A/µs	_	100	_	ns
Reverse recovery charge	Q _{rr}		_	0.2	_	μC

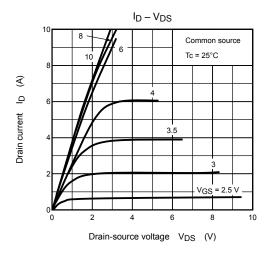
Flyback-Diode Rating and Characteristics (Ta = 25°C)

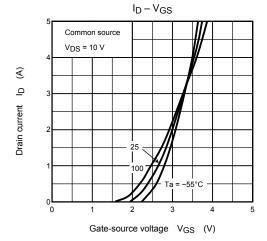
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Forward current	I _{FM}	_	_	_	3	Α
Reverse current	I _R	VR = 100 V	_	_	0.4	μA
Reverse voltage	V_{R}	I _R = 100 μA	100	_	_	V
Forward voltage	V _F	I _F = 0.5 A	_	_	1.8	V

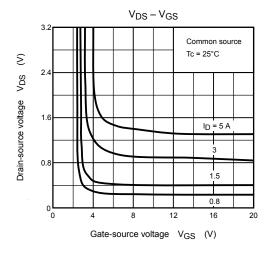
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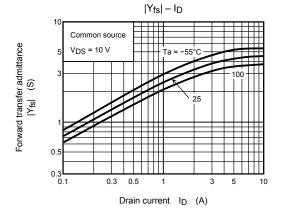


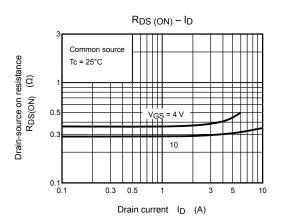




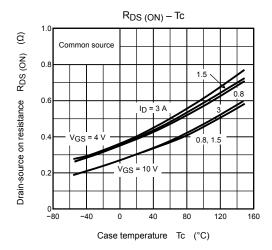


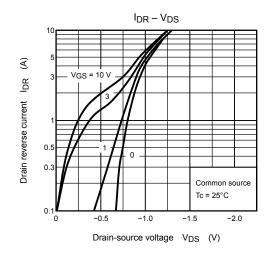


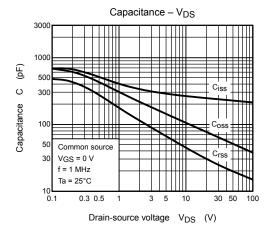


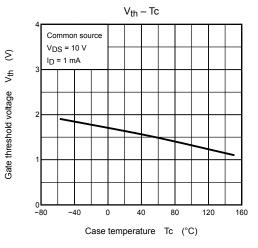


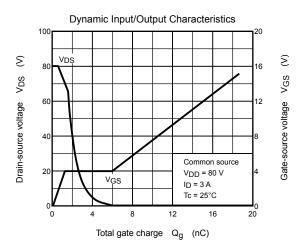
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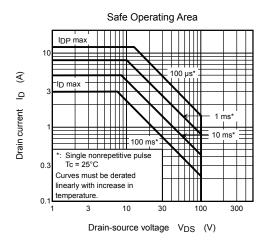




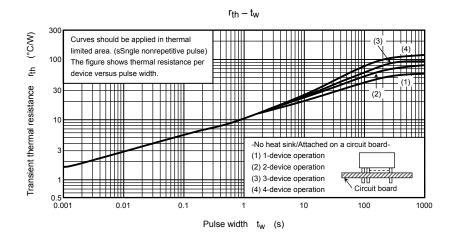


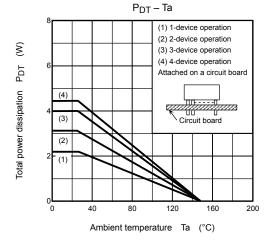


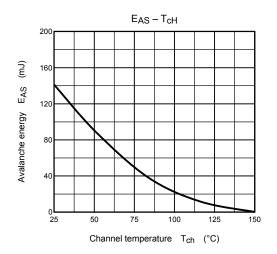


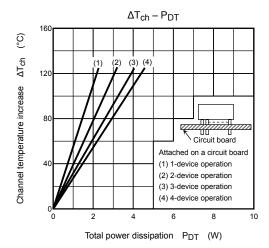


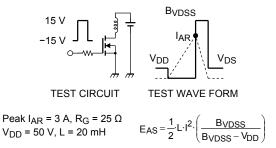
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